AN11051 Pin FMEA for HEF4000 family Rev. 1 — 28 April 2011

Application note

Document information

| Info | Content |
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| Keywords | FMEA, HEF4000, CMOS, wide operating supply range (3 V to 15 V) |
| Abstract | This application note provides a Failure Modes and Effects Analysis (FMEA) for the device pins of the NXP Semiconductors' HEF4000 family under typical failure situations |



Pin FMEA for HEF4000 family

Revision history

| Rev | Date | Description |
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Pin FMEA for HEF4000 family

1. Introduction

Though the HEF4000 series is one of the oldest CMOS logic families around, it is still frequently used in new designs because of its ease of design-in, wide operating supply range (3 V to 15 V), excellent noise immunity, and low power consumption. All of the standard functions are available, plus more specialized functions such as IEEE bus interfaces and PLL frequency synthesizers.

2. Pin FMEA

This application note provides a Failure Modes and Effects Analysis (FMEA) for the device pins of the NXP Semiconductor AUP family under typical failure situations such as a short-circuit to V_{DD} or V_{SS} or to a neighboring pin, or if a pin is left open.

Some HEF4000 family devices have special functions, that can have different behaviors. A failure is classified according to its effect on the HEF4000 device and the functionality of the application; see Table 1.

Table 1. Classification of failure effects

| Class | Failure effect |
|-------|--|
| Α | damage to device |
| | affects application functionality |
| В | no damage to device |
| | may affect application functionality |
| С | no damage to device |
| | no affect to application functionality |

Table 2. FMEA matrix for pin short-circuit to V_{DD}

| Pin | Class | Remarks |
|----------|-------|---|
| Input | В | normal operating condition, no damage, no leakage, may affect functionality |
| Output | С | if output defined HIGH, no damage, no leakage, no output level change |
| Output | А | if output defined LOW, short-circuits and high currents can damage device, output level changes |
| V_{SS} | В | short-circuits and high currents can damage device, will affect functionality |

Table 3. FMEA matrix for pin short-circuit to V_{SS}

| Pin | Class | Remarks |
|----------|-------|--|
| Input | В | normal operating condition, no damage, no leakage, may affect functionality |
| Output | С | if output defined LOW, no damage, no leakage, no output level change |
| Output | Α | if output defined HIGH, short-circuits and high currents can damage device, output level changes |
| V_{DD} | В | no damage to device, will affect functionality |

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Table 4. FMEA matrix for pin left open

| | · ···································· | | |
|----------|--|---|--|
| Pin | Class | Remarks | |
| Input | В | undefined operating condition, no damage, increases leakage, may affect functionality | |
| Output | С | normal operating condition, no damage, no leakage | |
| V_{SS} | В | undefined operating condition, no damage, increases leakage, will affect functionality | |
| V_{DD} | В | undefined operating condition, no damage, increases leakage (only for I/O types), will affect functionality | |

Table 5. FMEA matrix for pin short-circuits between neighboring pins

| Pin | Class | Remarks |
|------------------------------------|-------|--|
| Input to input | С | if inputs have same voltage levels: no damage, no leakage |
| | В | if inputs have different voltage levels: leakage increases, will affect functionality |
| Input to output | Α | if input and output have different voltage levels, can cause high current and can damage device, will affect functionality |
| | С | if input and output have same voltage levels, no damage, no leakage |
| Input to V _{SS} | - | see Table 3 |
| Input to V _{DD} | - | see Table 2 |
| Output to output | С | if outputs have same voltage levels, no damage, no leakage |
| | A | if outputs have different voltage levels, can cause high current and can damage device, will affect functionality |
| Output to input | - | same effect as 'input to output' condition |
| Output to V _{SS} | - | see Table 3 |
| Output to V _{DD} | - | see Table 2 |
| V _{SS} to V _{DD} | - | not applicable, these pins are not neighbors |

3. Abbreviations

Table 6. Abbreviations

| Acronym | Description |
|---------|---|
| CMOS | Complementary Metal-Oxide Semiconductor |
| FMEA | Failure Modes and Effects Analysis |
| PLL | Phase-Locked Loop |

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